

	Sonntag	Montag	Dienstag	Mittwoch	Donnerstag
9:30			MI 3: Analytical Transmission Electron Microscopy and Atom Probe Tomography	MI 5: Ion Beam Methods	MI 9: Functional Materials - Analysis with EBSD, X-Ray Kossel Diffraction and Related Methods
10:00		MI 2: Untersuchung von kondensierter Materie mittels Positronen- Annihilation	MI 4: Scanning Probe Microscopy	MI 6: X-ray Imaging, Holography and Tomography	MI 10: Crystallography in Nanoscience (KR jointly with MI)
11:00					
12:00					
Ab 13:00 Pause					
15:00		SYCM: Joint Symposium "Crystallography in Materials Science"	Festsitzung	MI 7: Synchrotron Radiation (Focus Session with Accelerator Physics)	MI 11: Crystallography in Materials Science (KR jointly with DF, MI)
16:00	Invited Tutorials				
17:00	MI 1: Festkörper- charakterisierung mit Positronen	Mitgliederversammlung des Fachverbandes MI		MI 8: Poster: Microanalysis and Microscopy	
18:00					
19:00					